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02/05/2002

U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM 10072734	FILING DATE 02/05/2002	CLASS 324	SUBCLASS 754	GAU 2858	EXAMINER KARLSEN
**APPLICANTS: Hembree David, Farnworth Warren; Akram Salman; Wood Alan; Doherty C; Krivy Andrew; 2829					
**CONTINUING DATA VERIFIED: THIS APPLICATION IS A DIV OF 09/929,388 08/14/2001 PAT 6,359,456 WHICH IS A DIV OF 09/303,367 04/30/1999 PAT 6,275,052 WHICH IS A DIV OF 08/797,719 02/11/1997 PAT 6,060,891					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB DO NOT PUBLISH		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO			
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		96-750			
Verified and Acknowledged Examiners's initials					
TITLE : Method for testing semiconductor wafers					

U.S. DEPT. OF COMM. / PAT & TM-PTO-436 (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING
Amount Due	Date Paid		Sheets Drwg. Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner
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